


<b>Search Notes</b> 	<b>Application/Control No.</b> 10651428	<b>Applicant(s)/Patent Under Reexamination</b> XIE, FEI
	<b>Examiner</b> YUWEN PAN	<b>Art Unit</b> 2618

SEARCHED			
Class	Subclass	Date	Examiner
455	412.1, 412.2	12/17/08	YP

SEARCH NOTES		
Search Notes	Date	Examiner
EAST text search	12/17/08	YP
updated search	3/5/09	YP

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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